


<b>Search Notes</b>  	<b>Application/Control No.</b>  10569075	<b>Applicant(s)/Patent Under Reexamination</b>  ONISHI ET AL.
	<b>Examiner</b>  Dalena Tran	<b>Art Unit</b>  3664

SEARCHED			
Class	Subclass	Date	Examiner
701	201, 208, 213		
455	41.2, 415, 435.1, 457, 500, 11,1 450, 566, 456.1, 500, 456.3, 426.2		
342	357.08, 357.14, 357.1, 357.13, 357.01		
370	328		
375	219		
340	995.1	4/25/10	DT

SEARCH NOTES			
Search Notes		Date	Examiner
EAST		4/25/10	DT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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